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Beam Interactions with Materials & Atoms

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Author index

Abbas, M.I., see Zhang, J. . . . 199 (2003) 291
Abstreiter, G., see Kolobov, A.V. . . . 199 (2003) 174
Adams, F., Synchrotron radiation micro-X-ray fluorescence analysis: A tool to increase accuracy in microscopic analysis . . . 199 (2003) 375
Adams, F., see Vekemans, B. . . . 199 (2003) 396
Adams, F., see Somogyi, A. . . . 199 (2003) 559
Akamatsu, K., see Fujii, K. . . . 199 (2003) 249
Akamatsu, K., K. Fujii and A. Yokoya, Infrared spectral change in 2-deoxy-D-ribose by irradiation with monochromatic photons around oxygen K-edge . . . 199 (2003) 328
Akamatsu, K., see Yokoya, A. . . . 199 (2003) 366
Akinaga, H., see Ofuchi, H. . . . 199 (2003) 227
Alatas, A., see Burkel, E. . . . 199 (2003) 151
Alp, E.E., see Burkel, E. . . . 199 (2003) 151
Anderson, E., see Schneider, G. . . . 199 (2003) 469
Ando, M., see Stevenson, A.W. . . . 199 (2003) 427
Aoyagi, S., see Kasatani, H. . . . 199 (2003) 49
Apiwatwaja, R., G. Hoyes, G. Isoyama, T. Ishii and W. Pairsuwan, Control system for Siam photon source . 199 (2003) 517
Arčon, I., M. Mozetič, A. Zalar, A. Kodre and J. Jagielski, EXAFS study of ion beam mixed Fe/Al multilayers 199 (2003) 222
Asokan, K., see Chandra, U. . . . 199 (2003) 185
Azevedo, G. de M., M.C. Ridgway, J. Betlehem, K.M. Yu, C.J. Glover and G.J. Foran, EXAFS measurements of metal-decorated nanocavities in Si . . . 199 (2003) 179
Azevedo, G. de M., see Ridgway, M.C. . . . 199 (2003) 235
Azough, F., see Tang, C.C. . . . 199 (2003) 64

Bader, S.D., see Kortright, J.B. . . . 199 (2003) 301
Baehtz, C., see Stir, M. . . . 199 (2003) 59
Banerjee, A., S.M. Chaudhari, R.V. Krishnan, B.A. Dasannacharya, T. Muro, Y. Saitoh, S. Imada and S. Suga, Magnetic circular dichroism of $LaMn_{1-x}Al_xO_{3+\delta}$ series of samples . . . 199 (2003) 308
Banerjee, A., S.M. Chaudhari, D.M. Phase and B.A. Dasannacharya, Photoelectron spectroscopy study on Li substituted NiO using PES beamline installed on Indus-1 . . . 199 (2003) 406
Banerjee, A., see Chaudhari, S.M. . . . 199 (2003) 520
Batchelor, D., see Evans, D.A. . . . 199 (2003) 475
Bates, W., see Schneider, G. . . . 199 (2003) 469
Beale, A.M. and G. Sankar, In situ characterization of iron phosphate and bismuth molybdate catalysts prepared by hydrothermal methods: An EDXRD and combined XRD/XAS study . . . 199 (2003) 504
Belakhovsky, M., see Faigel, G. . . . 199 (2003) 464
Benz, K.W., see Danilewsky, A.N. . . . 199 (2003) 71
Bérar, J.-F., see Hosokawa, S. . . . 199 (2003) 165
Berberich, F., W. Matz, U. Kreißig, N. Schell and A. Mücklich, Mechanism of degradation of surface hardening at elevated temperature in TiAlV-alloys by in situ synchrotron radiation diffraction . . . 199 (2003) 54
Betlehem, J., see Azevedo, G. de M. . . . 199 (2003) 179
Bhardwaj, D.M., see Parikh, P. . . . 199 (2003) 489
Bortel, G., see Faigel, G. . . . 199 (2003) 464
Boscherini, F., X-ray absorption studies of atomic environments in semiconductor nanostructures . . . 199 (2003) 169

PII: S0168-583X(02)02158-4

Bostedt, C., T. van Buuren, T.M. Willey, A.J. Nelson, N. Franco, T. Möller and L.J. Terminello, Characterization of Ge-nanocrystal films with photoelectron spectroscopy 199 (2003) 402
Bøttiger, J., see Schell, N. 199 (2003) 133
Bras, W., SAXS/WAXS experiments using extreme sample environments 199 (2003) 90
Brunner, K., see Kolobov, A.V. 199 (2003) 174
Bunge, H.J., see Wcislak, L. 199 (2003) 38
Burkel, E., see Jianu, A. 199 (2003) 44
Burkel, E., see Stir, M. 199 (2003) 59
Burkel, E., Dynamics of new materials probed by inelastic X-ray scattering 199 (2003) 143
Burkel, E., R. Nicula, U. Ponkratz, H. Sinn, A. Alatas and E.E. Alp, Lattice dynamics of Al-based quasicrystals studied by high-resolution inelastic X-ray scattering with synchrotron radiation 199 (2003) 151
Bushell, A., see Evans, D.A. 199 (2003) 475
Buth, G., see Simon, R. 199 (2003) 554

Cabailh, G., see Evans, D.A. 199 (2003) 475
Carlos, L.D., see Dahmouche, K. 199 (2003) 117
Carr, G.L., Dynamics of GaAs photocarriers probed with pulsed infrared synchrotron radiation 199 (2003) 323
Catlow, C.R.A., see Meneau, F. 199 (2003) 499
Chandra, U., J.C. Jan, J.W. Chiou, K. Asokan and W.F. Pong, Electronic structures of $La_{0.7-x}Cs_xCa_{0.3}MnO_3$ probed by X-ray absorption spectroscopy 199 (2003) 185
Chang, L.W., see Tsai, W.L. 199 (2003) 451
Chang, L.W., see Tsai, W.L. 199 (2003) 457
Chaudhari, S.M., see Banerjee, A. 199 (2003) 308
Chaudhari, S.M., see Banerjee, A. 199 (2003) 406
Chaudhari, S.M., A. Banerjee, D.M. Phase and B.A. Dasannacharya, Design of a polarised light beamline in the energy range of 30–4000 eV 199 (2003) 520
Chen, C.H., see Tsai, W.L. 199 (2003) 451
Chen, C.H., see Tsai, W.L. 199 (2003) 457
Chevallier, J., see Schell, N. 199 (2003) 133
Chew, E.P., see Moser, H.O. 199 (2003) 536
Chikaura, Y., K. Kajiwara, K. Morita, K. Mizuno, S. Iida, S. Kawado and Y. Suzuki, Formation of high energy white microbeam and its application to spectro-scattering topography 199 (2003) 67
Chikaura, Y., see Ozaki, T. 199 (2003) 81
Chikaura, Y., see Suzuki, C.K. 199 (2003) 85
Chiou, J.W., see Chandra, U. 199 (2003) 185
Chow, G.M., see Sun, C.J. 199 (2003) 156
Colón, G., see Kriventsov, V.V. 199 (2003) 216
Cookson, D.J., see Stevenson, A.W. 199 (2003) 427
Craievich, A.F., see Kellermann, G. 199 (2003) 112
Craievich, A.F., see Dahmouche, K. 199 (2003) 117
Cristol, S., see Meneau, F. 199 (2003) 499
Cross, J., see Kolobov, A.V. 199 (2003) 174

Dahmouche, K., M.C. Gonçalves, C.V. Santilli, V. de Zea Bermudez, L.D. Carlos and A.F. Craievich, Structure of luminescent mono and di-urethanesil nanocomposites doped with Eu^{3+} ions 199 (2003) 117
Dalela, S., see Singhal, R.K. 199 (2003) 280
Dalela, S., see Parikh, P. 199 (2003) 489
Danilewsky, A.N., R. Simon, A. Fauler, M. Fiederle and K.W. Benz, White beam X-ray topography at the synchrotron light source ANKA, Research Centre Karlsruhe 199 (2003) 71
Danilewsky, A.N., see Simon, R. 199 (2003) 550
Dasannacharya, B.A., see Banerjee, A. 199 (2003) 308
Dasannacharya, B.A., see Banerjee, A. 199 (2003) 406
Dasannacharya, B.A., see Chaudhari, S.M. 199 (2003) 520
Deki, S., see Kajinami, A. 199 (2003) 34
Demmel, F., see Hosokawa, S. 199 (2003) 161
Denbeaux, G., see Schneider, G. 199 (2003) 469
Desta, Y., see Hormes, J. 199 (2003) 332

de Zea Bermudez, V., see Dahmouche, K. . . . 199 (2003) 117
Dhanak, V.R., see Evans, D.A. . . . 199 (2003) 475
Ding, Y.F., see Mai, Z.H. . . . 199 (2003) 494
Doh, S.J., J.H. Je, J.S. Kim, K.Y. Kim, H.S. Kim, Y.D. Lee, J.M. Lee and Y. Hwu, Influence of Cr and Mo on the passivation of stainless steel 430 (18Cr) and 444 (18Cr–2Mo): In situ XANES study . . . 199 (2003) 211
Dolbnya, I.P., see Stevenson, A.W. . . . 199 (2003) 427
Doucet, J., Applied and industrial activities at the ESRF: Present status and future development . . . 199 (2003) 10
Drakopoulos, M., see Vekemans, B. . . . 199 (2003) 396
Drakopoulos, M., see Somogyi, A. . . . 199 (2003) 559

Eba, H., see Sakurai, K. . . . 199 (2003) 391
Evans, D.A., H.J. Steiner, A.R. Vearey-Roberts, A. Bushell, G. Cabailh, S. O'Brien, J.W. Wells, I.T. McGovern, V.R. Dhanak, T.U. Kampen, D.R.T. Zahn and D. Batchelor, Synchrotron radiation studies of inorganic–organic semiconductor interfaces . . . 199 (2003) 475

Faigel, G., M. Tegze, M. Belakhovsky, S. Marchesini and G. Bortel, X-ray holography . . . 199 (2003) 464
Fauler, A., see Danilewsky, A.N. . . . 199 (2003) 71
Fernandes, S., see Parikh, P. . . . 199 (2003) 489
Fiederle, M., see Danilewsky, A.N. . . . 199 (2003) 71
Fons, P., A. Yamada, K. Iwata, K. Matsubara, S. Niki, K. Nakahara and H. Takasu, An EXAFS and XANES study of MBE grown Cu-doped ZnO . . . 199 (2003) 190
Foran, G.J., see Azevedo, G. de M. . . . 199 (2003) 179
Foran, G.J., see Glover, C.J. . . . 199 (2003) 195
Foran, G.J., see Ridgway, M.C. . . . 199 (2003) 235
Franco, N., see Bostedt, C. . . . 199 (2003) 402
Freer, R., see Tang, C.C. . . . 199 (2003) 64
Frenkel, A., see Kolobov, A.V. . . . 199 (2003) 174
Frohlich, H., see Kobayashi, K. . . . 199 (2003) 348
Fujii, K., K. Akamatsu, Y. Muramatsu and A. Yokoya, X-ray absorption near edge structure of DNA bases around oxygen and nitrogen K-edge . . . 199 (2003) 249
Fujii, K., see Akamatsu, K. . . . 199 (2003) 328
Fujii, K., see Yokoya, A. . . . 199 (2003) 366
Fujimoto, I., see Ozaki, T. . . . 199 (2003) 81
Fujino, M., see Muramatsu, Y. . . . 199 (2003) 260
Fujioka, H., see Ofuchi, H. . . . 199 (2003) 231
Fullerton, E.E., see Kortright, J.B. . . . 199 (2003) 301
Fulthorpe, B.D., see Mai, Z.H. . . . 199 (2003) 494

Garbe, U., see Wcislak, L. . . . 199 (2003) 38
Garg, K.B., see Singhal, R.K. . . . 199 (2003) 280
Garg, K.B., see Parikh, P. . . . 199 (2003) 489
Garrett, R.F., see Stevenson, A.W. . . . 199 (2003) 427
Glover, C.J., see Azevedo, G. de M. . . . 199 (2003) 179
Glover, C.J., G.J. Foran and M.C. Ridgway, Structure of amorphous silicon investigated by EXAFS . . . 199 (2003) 195
Glover, C.J., see Ridgway, M.C. . . . 199 (2003) 235
Gonçalves, M.C., see Dahmouche, K. . . . 199 (2003) 117
Gorbunov, A., see Prokert, F. . . . 199 (2003) 123
Göttert, J., see Hormes, J. . . . 199 (2003) 332
Greaves, G.N., F. Meneau and G. Sankar, SAXS/WAXS and XAFS studies of zeolite stability . . . 199 (2003) 98
Greaves, G.N., see Landron, C. . . . 199 (2003) 481
Greaves, G.N., see Meneau, F. . . . 199 (2003) 499
Greif, J., see Hosokawa, S. . . . 199 (2003) 161
Groso, A., see Tsai, W.L. . . . 199 (2003) 436
Groza, J.R., see Jianu, A. . . . 199 (2003) 44
Gullikson, E.M., see Muramatsu, Y. . . . 199 (2003) 260
Guo, G.Y., see Hsu, L.-S. . . . 199 (2003) 200
Guo, Q., see Tanaka, T. . . . 199 (2003) 356

Gupta, R.P., see Parikh, P. . . . 199 (2003) 489
Gureyev, T.E., see Stevenson, A.W. . . . 199 (2003) 427

Hagelstein, M., see Simon, R. . . . 199 (2003) 554
Hagiwara, R., see Matsumoto, K. . . . 199 (2003) 29
Hambach, D., see Schneider, G. . . . 199 (2003) 469
Hara, M., see Setoyama, H. . . . 199 (2003) 275
Harada, Y., see Higuchi, T. . . . 199 (2003) 386
Hase, T.P.A., see Mai, Z.H. . . . 199 (2003) 494
Hasegawa, S., see Okudaira, K.K. . . . 199 (2003) 265
Hashimoto, E., see Yagi, S. . . . 199 (2003) 244
Hasse, W., see Schneider, G. . . . 199 (2003) 469
Hayashi, K., Y. Takahashi, E. Matsubara, M. Takemura, I. Mizushima, H. Tanida and M. Ishii, Peculiar structure of X-ray standing wave lines of Si:As . . . 199 (2003) 382
Hayashida, K., see Tanaka, T. . . . 199 (2003) 356
Heigl, F., see Starke, K. . . . 199 (2003) 313
Hellwig, O., see Kortright, J.B. . . . 199 (2003) 301
Hennet, L., see Landron, C. . . . 199 (2003) 481
Hidalgo, M.C., see Kriventsov, V.V. . . . 199 (2003) 216
Higuchi, T., T. Tsukamoto, S. Yamaguchi, K. Kobayashi, N. Sata, M. Ishigame and S. Shin, Observation of acceptor level of p-type $SrTiO_3$ by high-resolution soft-X-ray absorption spectroscopy . . . 199 (2003) 255
Higuchi, T., T. Takeuchi, T. Tsukamoto, Y. Harada, Y. Taguchi, Y. Tokura and S. Shin, Electron correlation energy of $La_xSr_{1-x}TiO_3$ by high-resolution soft-X-ray emission spectroscopy . . . 199 (2003) 386
Higuchi, T., see Kakemoto, H. . . . 199 (2003) 411
Hiramatsu, C.Q., see Suzuki, C.K. . . . 199 (2003) 85
Hiraya, A., see Shirasawa, K. . . . 199 (2003) 526
Hoffmann, K., see Schneider, G. . . . 199 (2003) 469
Hoffmann, N., see Schneider, G. . . . 199 (2003) 469
Hormes, J., J. Göttert, K. Lian, Y. Desta and L. Jian, Materials for LiGA and LiGA-based microsystems . . 199 (2003) 332
Hosokawa, S., J. Greif, F. Demmel and W.-C. Pilgrim, Phonon dynamics of liquid Si – inelastic X-ray scattering studies . . . 199 (2003) 161
Hosokawa, S., Y. Wang, M. Sakurai, J.-F. Bérar, W.-C. Pilgrim and K. Murase, Rigidity transitions and intermediate structures of Ge–Se glasses – An anomalous X-ray scattering study . . . 199 (2003) 165
Hoyes, G., see Apiwatwaja, R. . . . 199 (2003) 517
Hsu, L.-S., G.Y. Guo and Y.-K. Wang, Experimental and theoretical study of the electronic structure of Fe_3Al 199 (2003) 200
Hsu, P.C., see Tsai, W.L. . . . 199 (2003) 436
Hsu, P.C., see Kim, J.R. . . . 199 (2003) 441
Hsu, P.C., see Tsai, W.L. . . . 199 (2003) 451
Hwu, Y., see Doh, S.J. . . . 199 (2003) 211
Hwu, Y., see Lee, H.J. . . . 199 (2003) 342
Hwu, Y., see Tsai, W.L. . . . 199 (2003) 436
Hwu, Y., see Kim, J.R. . . . 199 (2003) 441
Hwu, Y., see Tsai, W.L. . . . 199 (2003) 451
Hwu, Y., see Tsai, W.L. . . . 199 (2003) 457
Hwu, Y.K., see Sun, C.J. . . . 199 (2003) 156
Hyodo, K., see Stevenson, A.W. . . . 199 (2003) 427

Ibrahim, K., see Zhang, J. . . . 199 (2003) 291
Ichikawa, M., see Kolobov, A.V. . . . 199 (2003) 174
Iida, S., see Chikaura, Y. . . . 199 (2003) 67
Iida, S., see Ozaki, T. . . . 199 (2003) 81
Ikenaga, E., see Sardar, S.A. . . . 199 (2003) 240
Ikenaga, E., see Yagi, S. . . . 199 (2003) 244
Imada, S., see Banerjee, A. . . . 199 (2003) 308
Imai, Y., see Mitsui, T. . . . 199 (2003) 75
Imaizumi, Y., see Ofuchi, H. . . . 199 (2003) 231
Imamura, M., see Okudaira, K.K. . . . 199 (2003) 265

Imamura, M., see Setoyama, H. . . . 199 (2003) 275
Isari, K., see Wada, S. . . . 199 (2003) 361
Ishigame, M., see Higuchi, T. . . . 199 (2003) 255
Ishii, H., see Shiozawa, H. . . . 199 (2003) 318
Ishii, M., Double resonance capacitance spectroscopy (DORCAS): A new experimental technique for assignment of X-ray absorption peaks to surface sites of semiconductor . . . 199 (2003) 205
Ishii, M., see Hayashi, K. . . . 199 (2003) 382
Ishii, T., see Apiwatwaja, R. . . . 199 (2003) 517
Ishii, T., see Pairsuwan, W. . . . 199 (2003) 546
Ishii, T., see Songsiriritthigul, P. . . . 199 (2003) 565
Isoyama, G., see Apiwatwaja, R. . . . 199 (2003) 517
Ito, Y., see Matsumoto, K. . . . 199 (2003) 29
Iwata, K., see Fons, P. . . . 199 (2003) 190

Jagielski, J., see Arčon, I. . . . 199 (2003) 222
Jain, D.C., see Singhal, R.K. . . . 199 (2003) 280
Jan, J.C., see Chandra, U. . . . 199 (2003) 185
Je, J.H., see Sun, C.J. . . . 199 (2003) 156
Je, J.H., see Doh, S.J. . . . 199 (2003) 211
Je, J.H., see Lee, H.J. . . . 199 (2003) 342
Je, J.H., see Tsai, W.L. . . . 199 (2003) 436
Je, J.H., see Kim, J.R. . . . 199 (2003) 441
Je, J.H., see Tsai, W.L. . . . 199 (2003) 451
Je, J.H., see Tsai, W.L. . . . 199 (2003) 457
Jeong, S.K., see Kim, J.R. . . . 199 (2003) 441
Jian, L., see Hormes, J. . . . 199 (2003) 332
Jiang, H.W., see Mai, Z.H. . . . 199 (2003) 494
Jiang, J.S., see Kortright, J.B. . . . 199 (2003) 301
Jianu, A., L. Stanciu, J.R. Groza, Ch. Lathe and E. Burkel, In situ analysis of phase transformation in sol–gel cogelified nanopowder mixture of Al_2O_3 and TiO_2 using synchrotron X-ray radiation diffraction experiments 199 (2003) 44
Ju, X., see Zhang, J. . . . 199 (2003) 291

Kagoshima, Y., see Matsui, J. . . . 199 (2003) 15
Kagoshima, Y., see Tsusaka, Y. . . . 199 (2003) 19
Kaindl, G., see Starke, K. . . . 199 (2003) 313
Kajinami, A., T. Kotake, S. Deki and S. Kohara, The structural analysis of manganese borate glass by high-energy X-ray diffraction measurement . . . 199 (2003) 34
Kajiwara, K., see Chikaura, Y. . . . 199 (2003) 67
Kajiwara, K., see Ozaki, T. . . . 199 (2003) 81
Kajiwara, K., see Suzuki, C.K. . . . 199 (2003) 85
Kakemoto, H., T. Higuchi, Y. Makita, Y. Kino, T. Tsukamoto, S. Shin, S. Wada and T. Tsurumi, Electronic structure of β-$FeSi_2$ obtained by maximum entropy method and photoemission spectroscopy . . . 199 (2003) 411
Kakizaki, A., see Songsiriritthigul, P. . . . 199 (2003) 565
Kamada, M., see Ouchi, I. . . . 199 (2003) 270
Kamada, M., see Soda, K. . . . 199 (2003) 416
Kamada, M., see Yuhara, J. . . . 199 (2003) 422
Kampen, T.U., see Evans, D.A. . . . 199 (2003) 475
Kang, H.S., see Kim, J.R. . . . 199 (2003) 441
Kasatani, H., S. Aoyagi, Y. Kuroiwa, K. Yagi, R. Katayama and H. Terauchi, Study of crystal structure at high temperature phase in KIO_3 crystal by synchrotron powder X-ray diffraction . . . 199 (2003) 49
Katayama, R., see Kasatani, H. . . . 199 (2003) 49
Kato, M., see Soda, K. . . . 199 (2003) 416
Katou, M., see Matsui, J. . . . 199 (2003) 15
Katou, M., see Tsusaka, Y. . . . 199 (2003) 19
Kawado, S., see Chikaura, Y. . . . 199 (2003) 67
Kellermann, G., A.F. Craievich, R. Neuenschwander and T.S. Plivelic, Setup for in situ WAXS/SAXS studies of the formation and growth of Bi nanodroplets and the melting of Bi nanocrystals using synchrotron radiation 199 (2003) 112

Kempenaers, L., see Vekemans, B. 199 (2003) 396
Kempson, V.C., see Moser, H.O. 199 (2003) 536
Kera, S., see Setoyama, H. 199 (2003) 275
Kikuta, S., see Mitsui, T. 199 (2003) 75
Kim, H.S., see Doh, S.J. 199 (2003) 211
Kim, J.S., see Doh, S.J. 199 (2003) 211
Kim, K.Y., see Doh, S.J. 199 (2003) 211
Kim, J.R., H.S. Kang, H.J. Lee, J.H. Je, S.K. Jeong, W.-L. Tsai, P.C. Hsu and Y. Hwu, Real-time microradiology of disintegration of iron ore sinteres 199 (2003) 441
Kimura, S., see Matsui, J. 199 (2003) 15
Kino, Y., see Kakemoto, H. 199 (2003) 411
Klein, H., see Wcislak, L. 199 (2003) 38
Knapp, M., see Stir, M. 199 (2003) 59
Kobayashi, K., see Higuchi, T. 199 (2003) 255
Kobayashi, K., N. Usami, I. Sasaki, H. Frohlich and C. Le Sech, Study of Auger effect in DNA when bound to molecules containing platinum. A possible application to hadrontherapy 199 (2003) 348
Kochubey, D.I., see Kriventsov, V.V. 199 (2003) 216
Kodre, A., see Arčon, I. 199 (2003) 222
Kohara, S. and K. Suzuya, High-energy X-ray diffraction studies of disordered materials 199 (2003) 23
Kohara, S., see Matsumoto, K. 199 (2003) 29
Kohara, S., see Kajinami, A. 199 (2003) 34
Kolobov, A.V., H. Oyanagi, A. Frenkel, I. Robinson, J. Cross, S. Wei, K. Brunner, G. Abstreiter, Y. Maeda, A. Shklyaev, M. Ichikawa, S. Yamasaki and K. Tanaka, Local structure of Ge/Si nanostructures: Uniqueness of XAFS spectroscopy 199 (2003) 174
Kong, J.R., see Moser, H.O. 199 (2003) 536
Kortright, J.B., J.S. Jiang, S.D. Bader, O. Hellwig, D.T. Marguiles and E.E. Fullerton, Magnetism in heterogeneous thin film systems: Resonant X-ray scattering studies 199 (2003) 301
Kotake, T., see Kajinami, A. 199 (2003) 34
Koyama, I. and A. Momose, Simulation study of spatial resolution in phase-contrast X-ray imaging with Takagi–Taupin equation 199 (2003) 446
Kreißig, U., see Berberich, F. 199 (2003) 54
Krishnan, R.V., see Banerjee, A. 199 (2003) 308
Kriventsov, V.V., D.I. Kochubey, M.V. Tsodikov, J.A. Navio, M.C. Hidalgo, G. Colón, Yu.V. Maksimov and I.P. Suzdalev, XAFS study of an intermetallic $TiFe_{0.95}Zr_{0.03}Mo_{0.02}$ system for CO_2 conversion 199 (2003) 216
Krupin, O., see Starke, K. 199 (2003) 313
Kurihara, H., see Matsui, J. 199 (2003) 15
Kurihara, H., see Tsusaka, Y. 199 (2003) 19
Kuroiwa, Y., see Kasatani, H. 199 (2003) 49
Kvick, Å., Materials science research at the European Synchrotron Radiation Facility 199 (2003) 531

Lai, B., see Stevenson, A.W. 199 (2003) 427
Lai, W.Y., see Mai, Z.H. 199 (2003) 494
Landron, C., L. Hennet, D. Thiaudiere, D.L. Price and G.N. Greaves, Structure of liquid oxides at very high temperatures 199 (2003) 481
Lathe, C., see Stir, M. 199 (2003) 59
Lathe, Ch., see Jianu, A. 199 (2003) 44
Lee, H.J., J.H. Je, Y. Hwu and W.L. Tsai, Synchrotron X-ray induced solution precipitation of nanoparticles 199 (2003) 342
Lee, H.J., see Kim, J.R. 199 (2003) 441
Lee, J.M., see Doh, S.J. 199 (2003) 211
Lee, Y.D., see Doh, S.J. 199 (2003) 211
Le Sech, C., see Kobayashi, K. 199 (2003) 348
Li, M.H., see Mai, Z.H. 199 (2003) 494
Li, Z.W., see Moser, H.O. 199 (2003) 536
Lian, K., see Hormes, J. 199 (2003) 332
Lin, H.M., see Tsai, W.L. 199 (2003) 457
Liu, C.X., see Mai, Z.H. 199 (2003) 494
Lodha, G.S., see Nayak, M. 199 (2003) 128
Luo, G.M., see Mai, Z.H. 199 (2003) 494

Maeda, Y., see Kolobov, A.V. . . . 199 (2003) 174
Mai, Z.H., G.M. Luo, C.X. Liu, M.H. Li, H.W. Jiang, W.Y. Lai, J. Wang, Y.F. Ding, T.P.A. Hase, B.D. Fulthorpe and B.K. Tanner, Structural and chemical diagnosis of magnetic multilayers by RAFS and XRF techniques . . . 199 (2003) 494
Makita, Y., see Kakemoto, H. . . . 199 (2003) 411
Maksimov, Yu.V., see Kriventsov, V.V. . . . 199 (2003) 216
Manago, T., see Ofuchi, H. . . . 199 (2003) 227
Marchesini, S., see Faigel, G. . . . 199 (2003) 464
Margaritondo, G., see Tsai, W.L. . . . 199 (2003) 436
Margaritondo, G., see Tsai, W.L. . . . 199 (2003) 451
Margaritondo, G., see Tsai, W.L. . . . 199 (2003) 457
Marguiles, D.T., see Kortright, J.B. . . . 199 (2003) 301
Mase, K., see Okudaira, K.K. . . . 199 (2003) 265
Mase, K., see Setoyama, H. . . . 199 (2003) 275
Matsubara, E., see Hayashi, K. . . . 199 (2003) 382
Matsubara, K., see Fons, P. . . . 199 (2003) 190
Matsuda, T.D., see Shiozawa, H. . . . 199 (2003) 318
Matsui, J., Y. Tsusaka, K. Yokoyama, S. Takeda, M. Katou, H. Kurihara, K. Watanabe, Y. Kagoshima and S. Kimura, Measurement of minute local strain in semiconductor materials and electronic devices by using a highly parallel X-ray microbeam . . . 199 (2003) 15
Matsui, J., see Tsusaka, Y. . . . 199 (2003) 19
Matsumoto, E., see Yoshida, A. . . . 199 (2003) 370
Matsumoto, K., R. Hagiwara, Y. Ito, S. Kohara and K. Suzuya, Structural analysis of 1-ethyl-3-methylimidazolium bifluoride melt . . . 199 (2003) 29
Matsumura, K., see Yagi, S. . . . 199 (2003) 244
Matz, W., see Berberich, F. . . . 199 (2003) 54
Matz, W., see Schell, N. . . . 199 (2003) 133
McGovern, I.T., see Evans, D.A. . . . 199 (2003) 475
Meneau, F., see Greaves, G.N. . . . 199 (2003) 98
Meneau, F., G. Sankar, N. Morgante, S. Cristol, C.R.A. Catlow, J.M. Thomas and G.N. Greaves, Characterization of zinc oxide nanoparticles encapsulated into zeolite-Y: An in-situ combined X-ray diffraction, XAFS, and SAXS study . . . 199 (2003) 499
Mitsui, T., Y. Imai and S. Kikuta, Stroboscopic topographies on iron borate crystal in 9.6 MHz rf magnetic field 199 (2003) 75
Miyahara, T., see Shiozawa, H. . . . 199 (2003) 318
Mizuguchi, M., see Ofuchi, H. . . . 199 (2003) 227
Mizuno, K., see Chikaura, Y. . . . 199 (2003) 67
Mizuno, K., see Ozaki, T. . . . 199 (2003) 81
Mizusawa, M. and K. Sakurai, Specular and non-specular X-ray reflection from a single-crystal molybdenum mirror surface . . . 199 (2003) 139
Mizushima, I., see Hayashi, K. . . . 199 (2003) 382
Modi, M.H., see Nayak, M. . . . 199 (2003) 128
Möller, T., see Bostedt, C. . . . 199 (2003) 402
Momose, A., see Koyama, I. . . . 199 (2003) 446
Morgante, N., see Meneau, F. . . . 199 (2003) 499
Morita, K., see Chikaura, Y. . . . 199 (2003) 67
Morita, K., see Soda, K. . . . 199 (2003) 416
Moser, H.O., see Tsai, W.L. . . . 199 (2003) 436
Moser, H.O., E.P. Chew, V.C. Kempson, J.R. Kong, Z.W. Li, T. Nyunt, H.J. Qian, R. Rossmanith, P.H. Tor, O. Wilhelmi, P. Yang, H.W. Zheng and I.J. Underhay, Singapore Synchrotron Light Source – Status, first results, program . . . 199 (2003) 536
Mozetič, M., see Arčon, I. . . . 199 (2003) 222
Mücklich, A., see Berberich, F. . . . 199 (2003) 54
Muneyoshi, T., see Shirasawa, K. . . . 199 (2003) 526
Muramatsu, Y., see Fujii, K. . . . 199 (2003) 249
Muramatsu, Y., M. Fujino, T. Yamamoto, E.M. Gullikson and R.C.C. Perera, Soft X-ray emission and absorption spectroscopy in the Si *L* region of polysilanes . . . 199 (2003) 260
Murase, K., see Hosokawa, S. . . . 199 (2003) 165

Murase, T., see Setoyama, H. . . . 199 (2003) 275
Muro, T., see Banerjee, A. . . . 199 (2003) 308
Muro, T., see Shiozawa, H. . . . 199 (2003) 318

Nachimuthu, P., see Schneider, G. . . . 199 (2003) 469
Nakahara, K., see Fons, P. . . . 199 (2003) 190
Nakai, I., see Ouchi, I. . . . 199 (2003) 270
Nakamura, D., see Yuhara, J. . . . 199 (2003) 422
Nakano, Y., see Yagi, S. . . . 199 (2003) 244
Nandedkar, R.V., see Nayak, M. . . . 199 (2003) 128
Nandedkar, R.V. and K.J.S. Sawhney, Status of Indus-1 and Indus-2 beamlines . . . 199 (2003) 541
Navio, J.A., see Kriventsov, V.V. . . . 199 (2003) 216
Nayak, M., M.H. Modi, G.S. Lodha, A.K. Shrivastava, P. Tripathi, A.K. Sinha, K.J.S. Sawhney and R.V. Nandedkar, Characterization of molybdenum/silicon X-ray multilayers . . . 199 (2003) 128
Nelson, A.J., see Bostedt, C. . . . 199 (2003) 402
Neuenschwander, R., see Kellermann, G. . . . 199 (2003) 112
Nicula, R., see Stir, M. . . . 199 (2003) 59
Nicula, R., see Burkel, E. . . . 199 (2003) 151
Niki, S., see Fons, P. . . . 199 (2003) 190
Nishio, M., see Tanaka, T. . . . 199 (2003) 356
Noh, D.Y., see Sun, C.J. . . . 199 (2003) 156
Nyunt, T., see Moser, H.O. . . . 199 (2003) 536

O'Brien, S., see Evans, D.A. . . . 199 (2003) 475
Obu, K., see Shiozawa, H. . . . 199 (2003) 318
Ofuchi, H., M. Mizuguchi, K. Ono, M. Oshima, H. Akinaga and T. Manago, Fluorescence extended X-ray absorption fine structure analysis of half-metallic ferromagnet "zinc-blende CrAs" grown on GaAs by molecular beam epitaxy . . . 199 (2003) 227
Ofuchi, H., Y. Imaizumi, H. Sugawara, H. Fujioka, M. Oshima and Y. Takeda, Fluorescence XAFS study on local structures around Tb ions implanted in SiO_2 on Si . . . 199 (2003) 231
Ogawa, H., see Tanaka, T. . . . 199 (2003) 356
Ohara, K., see Okudaira, K.K. . . . 199 (2003) 265
Okada, H., see Yoshida, A. . . . 199 (2003) 370
Okudaira, K.K., K. Ohara, H. Setoyama, T. Suzuki, Y. Sakamoto, M. Imamura, S. Hasegawa, K. Mase and N. Ueno, Excited states of perfluorinated oligo(*p*-phenylene) by inner-shell excitation . . . 199 (2003) 265
Okudaira, K.K., see Setoyama, H. . . . 199 (2003) 275
Ono, K., see Ofuchi, H. . . . 199 (2003) 227
Oshima, M., see Ofuchi, H. . . . 199 (2003) 227
Oshima, M., see Ofuchi, H. . . . 199 (2003) 231
Ouchi, I., I. Nakai and M. Kamada, Anisotropic absorption spectra of polyester films in the ultraviolet and vacuum ultraviolet regions . . . 199 (2003) 270
Oyanagi, H., see Kolobov, A.V. . . . 199 (2003) 174
Ozaki, T., I. Fujimoto, K. Mizuno, S. Iida, K. Kajiwara, T. Taira, J. Yoshimura, T. Shimura and Y. Chikaura, Low temperature Laue topography of strontium titanate at SPring-8 . . . 199 (2003) 81

Paganin, D., see Stevenson, A.W. . . . 199 (2003) 427
Pairsuwan, W., see Apiwatwaja, R. . . . 199 (2003) 517
Pairsuwan, W. and T. Ishii, Status of the Siam Photon Source . . . 199 (2003) 546
Pairsuwan, W., see Songsiriritthigul, P. . . . 199 (2003) 565
Pan, H.B., see Xu, P.S. . . . 199 (2003) 286
Parikh, P., N.L. Saini, S. Dalela, D.M. Bhardwaj, S. Fernandes, R.P. Gupta and K.B. Garg, Using XAFS, EDAX and AFM in comparative study of various natural and synthetic emeralds . . . 199 (2003) 489
Pearson, A., see Schneider, G. . . . 199 (2003) 469
Perera, R.C.C., see Muramatsu, Y. . . . 199 (2003) 260
Phase, D.M., see Banerjee, A. . . . 199 (2003) 406
Phase, D.M., see Chaudhari, S.M. . . . 199 (2003) 520
Pilgrim, W.-C., see Hosokawa, S. . . . 199 (2003) 161

Pilgrim, W.-C., see Hosokawa, S. . . . 199 (2003) 165
Ping, Y., see Tsai, W.L. . . . 199 (2003) 436
Plivelic, T.S., see Kellermann, G. . . . 199 (2003) 112
Pong, W.F., see Chandra, U. . . . 199 (2003) 185
Ponkratz, U., see Burkel, E. . . . 199 (2003) 151
Price, D.L., see Landron, C. . . . 199 (2003) 481
Prieto, J.E., see Starke, K. . . . 199 (2003) 313
Prokert, F., N. Schell and A. Gorbunov, Use of anomalous scattering for synchrotron X-ray reflectivity studies of Fe–Cr and Co–Cu double layers . . . 199 (2003) 123

Qian, H.J., see Moser, H.O. . . . 199 (2003) 536

Rau, C., see Stevenson, A.W. . . . 199 (2003) 427
Reid, J.B., see Suzuki, C.K. . . . 199 (2003) 85
Richardson, D., see Schneider, G. . . . 199 (2003) 469
Ridgway, M.C., see Azevedo, G. de M. . . . 199 (2003) 179
Ridgway, M.C., see Glover, C.J. . . . 199 (2003) 195
Ridgway, M.C., G. de M. Azevedo, C.J. Glover, K.M. Yu and G.J. Foran, Common structure in amorphised compound semiconductors . . . 199 (2003) 235
Riekel, C., Applications of micro-SAXS/WAXS to study polymer fibers . . . 199 (2003) 106
Roberts, M.A., see Tang, C.C. . . . 199 (2003) 64
Robinson, I., see Kolobov, A.V. . . . 199 (2003) 174
Rossmanith, R., see Moser, H.O. . . . 199 (2003) 536

Saini, N.L., see Singhal, R.K. . . . 199 (2003) 280
Saini, N.L., see Parikh, P. . . . 199 (2003) 489
Saitoh, Y., see Banerjee, A. . . . 199 (2003) 308
Saitoh, Y., see Shiozawa, H. . . . 199 (2003) 318
Sakamoto, Y., see Okudaira, K.K. . . . 199 (2003) 265
Sako, E.O., see Wada, S. . . . 199 (2003) 361
Sakurai, K., see Mizusawa, M. . . . 199 (2003) 139
Sakurai, K. and H. Eba, Chemical characterization using relative intensity of manganese $K\beta'$ and $K\beta_5$ X-ray fluorescence . . . 199 (2003) 391
Sakurai, M., see Hosokawa, S. . . . 199 (2003) 165
Salmassi, F., see Schneider, G. . . . 199 (2003) 469
Sankar, G., see Greaves, G.N. . . . 199 (2003) 98
Sankar, G., see Meneau, F. . . . 199 (2003) 499
Sankar, G., see Beale, A.M. . . . 199 (2003) 504
Santilli, C.V., see Dahmouche, K. . . . 199 (2003) 117
Sardar, S.A., J.A. Syed, E. Ikenaga, S. Yagi, T. Sekitani, S. Wada, M. Taniguchi and K. Tanaka, Orientation and charge transfer upon adsorption of ethanethiol on Cu(1 1 1) surface at 85 K . . . 199 (2003) 240
Sardar, S.A., see Yagi, S. . . . 199 (2003) 244
Sasaki, I., see Kobayashi, K. . . . 199 (2003) 348
Sata, N., see Higuchi, T. . . . 199 (2003) 255
Sato, H., see Shiozawa, H. . . . 199 (2003) 318
Sawhney, K.J.S., see Nayak, M. . . . 199 (2003) 128
Sawhney, K.J.S., see Nandedkar, R.V. . . . 199 (2003) 541
Schell, N., see Berberich, F. . . . 199 (2003) 54
Schell, N., see Prokert, F. . . . 199 (2003) 123
Schell, N., J. Bøttiger, W. Matz and J. Chevallier, Growth mode and texture development in TiN films during magnetron sputtering – An in situ synchrotron radiation study . . . 199 (2003) 133
Schneider, G., G. Denbeaux, E. Anderson, W. Bates, F. Salmassi, P. Nachimuthu, A. Pearson, D. Richardson, D. Hambach, N. Hoffmann, W. Hasse and K. Hoffmann, Electromigration in integrated circuit interconnects studied by X-ray microscopy . . . 199 (2003) 469
Schneider, J.R., see Wcislak, L. . . . 199 (2003) 38
Sekhar, B., see Singhal, R.K. . . . 199 (2003) 280
Sekiguchi, T., see Wada, S. . . . 199 (2003) 361

Sekitani, T., see Sardar, S.A. . . . 199 (2003) 240
Sekitani, T., see Wada, S. . . . 199 (2003) 361
Setoyama, H., see Okudaira, K.K. . . . 199 (2003) 265
Setoyama, H., S. Kera, T. Murase, M. Imamura, K. Mase, K.K. Okudaira, M. Hara and N. Ueno, Partial ion yield and NEXAFS of 2-(perfluorooctyl)ethanethiol self-assembled monolayer: Comparison with PTFE results . . . 199 (2003) 275
Shenoy, G.K., Impact of next-generation synchrotron radiation sources on materials research . . . 199 (2003) 1
Shi, C.S., see Xu, P.S. . . . 199 (2003) 286
Shimura, T., see Ozaki, T. . . . 199 (2003) 81
Shin, S., see Higuchi, T. . . . 199 (2003) 255
Shin, S., see Higuchi, T. . . . 199 (2003) 386
Shin, S., see Kakemoto, H. . . . 199 (2003) 411
Shinohara, A.H., see Suzuki, C.K. . . . 199 (2003) 85
Shiozawa, H., T. Miyahara, H. Ishii, Y. Takayama, K. Obu, T. Muro, Y. Saitoh, T.D. Matsuda, H. Sugawara and H. Sato, Measurements of temperature dependence of "localized susceptibility" . . . 199 (2003) 318
Shirasawa, K., N.V. Smolyakov, A. Hiraya and T. Muneyoshi, Edge radiation as IR–UV source . . . 199 (2003) 526
Shklyaev, A., see Kolobov, A.V. . . . 199 (2003) 174
Shrivastava, A.K., see Nayak, M. . . . 199 (2003) 128
Simionovici, A., see Vekemans, B. . . . 199 (2003) 396
Simionovici, A., see Somogyi, A. . . . 199 (2003) 559
Simon, R., see Danilewsky, A.N. . . . 199 (2003) 71
Simon, R. and A.N. Danilewsky, The experimental station for white beam X-ray topography at the synchrotron light source ANKA, Karlsruhe . . . 199 (2003) 550
Simon, R., G. Buth and M. Hagelstein, The X-ray-fluorescence facility at ANKA, Karlsruhe: Minimum detection limits and micro probe capabilities . . . 199 (2003) 554
Singhal, R.K., N.L. Saini, S. Dalela, B. Sekhar, D.C. Jain and K.B. Garg, Study of anomalous temperature dependence of itinerant holes in under- and overdoped $La_{2-x}Sr_xCuO_4$ single crystals using polarised soft X-ray absorption spectroscopy . . . 199 (2003) 280
Sinha, A.K., see Nayak, M. . . . 199 (2003) 128
Sinn, H., see Burkel, E. . . . 199 (2003) 151
Smolyakov, N.V., see Shirasawa, K. . . . 199 (2003) 526
Snigirev, A., see Stevenson, A.W. . . . 199 (2003) 427
Snigireva, I., see Stevenson, A.W. . . . 199 (2003) 427
Soda, K., see Yagi, S. . . . 199 (2003) 244
Soda, K., J. Yuhara, T. Takada, O. Yoshimoto, M. Kato, S. Yagi, K. Morita and M. Kamada, Core-level photoelectron study of Si(1 1 1) $\sqrt{7} \times \sqrt{3}$-(Pb, Sn) surface . . . 199 (2003) 416
Soda, K., see Yuhara, J. . . . 199 (2003) 422
Somogyi, A., see Vekemans, B. . . . 199 (2003) 396
Somogyi, A., M. Drakopoulos, B. Vekemans, L. Vincze, A. Simionovici and F. Adams, Effects of beamline components (undulator, monochromator, focusing device) on the beam intensity at ID18F (ESRF) . . . 199 (2003) 559
Songsiriritthigul, P., W. Pairsuwan, T. Ishii and A. Kakizaki, Beamlines at Siam photon laboratory . . . 199 (2003) 565
Soo, E.W., see Sun, C.J. . . . 199 (2003) 156
Stanciu, L., see Jianu, A. . . . 199 (2003) 44
Stankevich, V.G., The materials science program of the Kurchatov synchrotron radiation source . . . 199 (2003) 569
Starke, K., F. Heigl, J.E. Prieto, O. Krupin and G. Kaindl, Soft X-ray magneto-optics in lanthanides at the $N_{4,5}$- and $M_{4,5}$-thresholds . . . 199 (2003) 313
Steiner, H.J., see Evans, D.A. . . . 199 (2003) 475
Stevenson, A.W., T.E. Gureyev, D. Paganin, S.W. Wilkins, T. Weitkamp, A. Snigirev, C. Rau, I. Snigireva, H.S. Youn, I.P. Dolbnya, W. Yun, B. Lai, R.F. Garrett, D.J. Cookson, K. Hyodo and M. Ando, Phase-contrast X-ray imaging with synchrotron radiation for materials science applications . . . 199 (2003) 427
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Stirling, W.G., Synchrotron X-ray magnetic scattering . . . 199 (2003) 295
Suga, S., see Banerjee, A. . . . 199 (2003) 308
Sugawara, H., see Ofuchi, H. . . . 199 (2003) 231
Sugawara, H., see Shiozawa, H. . . . 199 (2003) 318
Sumii, R., see Wada, S. . . . 199 (2003) 361

Sun, C.J., G.M. Chow, J.P. Wang, E.W. Soo, D.Y. Noh, J.H. Je and Y.K. Hwu, A structural study of effects of NiP seed layer on the magnetic properties of CoCrPt/Ti/NiP perpendicular magnetic films 199 (2003) 156
Sun, Y.M., see Xu, P.S. 199 (2003) 286
Suzdalev, I.P., see Kriventsov, V.V. 199 (2003) 216
Suzuki, C.K., A.H. Shinohara, C.Q. Hiramatsu, J.-i. Yoshimura, J.B. Reid, K. Kajiwara and Y. Chikaura, High resolution X-ray Laue topography of thick quartz crystals at SPring-8 . . . . . 199 (2003) 85
Suzuki, T., see Okudaira, K.K. 199 (2003) 265
Suzuki, Y., see Chikaura, Y. 199 (2003) 67
Suzuya, K., see Kohara, S. 199 (2003) 23
Suzuya, K., see Matsumoto, K. 199 (2003) 29
Syed, J.A., see Sardar, S.A. 199 (2003) 240
Syed, J.A., see Yagi, S. 199 (2003) 244

Taguchi, Y., see Higuchi, T. 199 (2003) 386
Taira, T., see Ozaki, T. 199 (2003) 81
Takada, T., see Soda, K. 199 (2003) 416
Takahashi, Y., see Hayashi, K. 199 (2003) 382
Takasu, H., see Fons, P. 199 (2003) 190
Takayama, Y., see Shiozawa, H. 199 (2003) 318
Takeda, S., see Matsui, J. 199 (2003) 15
Takeda, S., see Tsusaka, Y. 199 (2003) 19
Takeda, Y., see Ofuchi, H. 199 (2003) 231
Takemura, M., see Hayashi, K. 199 (2003) 382
Takeuchi, T., see Higuchi, T. 199 (2003) 386
Tanaka, K., see Kolobov, A.V. 199 (2003) 174
Tanaka, K., see Sardar, S.A. 199 (2003) 240
Tanaka, K., see Yagi, S. 199 (2003) 244
Tanaka, K., see Wada, S. 199 (2003) 361
Tanaka, T., K. Hayashida, S. Wang, Q. Guo, M. Nishio and H. Ogawa, Photoluminescence properties of ZnTe homoepitaxial layers grown by synchrotron-radiation-excited growth using nitrogen carrier gas 199 (2003) 356
Tang, C.C., M.A. Roberts, F. Azough and R. Freer, Structural studies of $Ba_{6-3x}Nd_{8+2x}Ti_{18}O_{54}$ microwave dielectric ceramics at $T = 10$–295 K 199 (2003) 64
Tanida, H., see Hayashi, K. 199 (2003) 382
Taniguchi, M., see Sardar, S.A. 199 (2003) 240
Taniguchi, M., see Yagi, S. 199 (2003) 244
Taniguchi, M., Hiroshima Synchrotron Radiation Center – An outline and scientific activities 199 (2003) 574
Tanner, B.K., see Mai, Z.H. 199 (2003) 494
Tegze, M., see Faigel, G. 199 (2003) 464
Terauchi, H., see Kasatani, H. 199 (2003) 49
Terminello, L.J., see Bostedt, C. 199 (2003) 402
Thiaudiere, D., see Landron, C. 199 (2003) 481
Thomas, J.M., see Meneau, F. 199 (2003) 499
Tokura, Y., see Higuchi, T. 199 (2003) 386
Tor, P.H., see Moser, H.O. 199 (2003) 536
Traykova, T., see Stir, M. 199 (2003) 59
Tripathi, P., see Nayak, M. 199 (2003) 128
Tsai, W.L., see Lee, H.J. 199 (2003) 342
Tsai, W.L., P.C. Hsu, Y. Hwu, J.H. Je, Y. Ping, H.O. Moser, A. Groso and G. Margaritondo, Edge-enhanced radiology with broadband synchrotron X-rays 199 (2003) 436
Tsai, W.-L., see Kim, J.R. 199 (2003) 441
Tsai, W.L., P.C. Hsu, Y. Hwu, C.H. Chen, L.W. Chang, J.H. Je and G. Margaritondo, Real-time observation of Zn electro-deposition with high-resolution microradiology 199 (2003) 451
Tsai, W.L., Y. Hwu, C.H. Chen, L.W. Chang, J.H. Je, H.M. Lin and G. Margaritondo, Grain boundary imaging, gallium diffusion and the fracture behavior of Al–Zn Alloy – An in situ study 199 (2003) 457
Tsodikov, M.V., see Kriventsov, V.V. 199 (2003) 216
Tsukamoto, T., see Higuchi, T. 199 (2003) 255
Tsukamoto, T., see Higuchi, T. 199 (2003) 386

Tsukamoto, T., see Kakemoto, H. 199 (2003) 411
Tsurumi, T., see Kakemoto, H. 199 (2003) 411
Tsusaka, Y., see Matsui, J. 199 (2003) 15
Tsusaka, Y., M. Urakawa, K. Yokoyama, S. Takeda, M. Katou, H. Kurihara, F. Yoshida, K. Watanabe, Y. Kagoshima and J. Matsui, Estimation of bonded silicon-on-insulator wafers by means of diffractometry using a parallel X-ray microbeam 199 (2003) 19

Ueno, N., see Okudaira, K.K. 199 (2003) 265
Ueno, N., see Setoyama, H. 199 (2003) 275
Underhay, I.J., see Moser, H.O. 199 (2003) 536
Urakawa, M., see Tsusaka, Y. 199 (2003) 19
Usami, N., see Kobayashi, K. 199 (2003) 348

van Buuren, T., see Bostedt, C. 199 (2003) 402
Vearey-Roberts, A.R., see Evans, D.A. 199 (2003) 475
Vekemans, B., L. Vincze, A. Somogyi, M. Drakopoulos, L. Kempenaers, A. Simionovici and F. Adams, Quantitative X-ray fluorescence analysis at the ESRF ID18F microprobe 199 (2003) 396
Vekemans, B., see Somogyi, A. 199 (2003) 559
Vincze, L., see Vekemans, B. 199 (2003) 396
Vincze, L., see Somogyi, A. 199 (2003) 559

Wada, S., see Sardar, S.A. 199 (2003) 240
Wada, S., E.O. Sako, R. Sumii, S. Waki, K. Isari, T. Sekiguchi, T. Sekitani and K. Tanaka, Active control of site specificity in ion desorption by core excitation 199 (2003) 361
Wada, S., see Kakemoto, H. 199 (2003) 411
Wakahara, A., see Yoshida, A. 199 (2003) 370
Waki, S., see Wada, S. 199 (2003) 361
Wang, J., see Mai, Z.H. 199 (2003) 494
Wang, J.P., see Sun, C.J. 199 (2003) 156
Wang, S., see Tanaka, T. 199 (2003) 356
Wang, Y., see Hosokawa, S. 199 (2003) 165
Wang, Y.-K., see Hsu, L.-S. 199 (2003) 200
Watanabe, K., see Matsui, J. 199 (2003) 15
Watanabe, K., see Tsusaka, Y. 199 (2003) 19
Wcislak, L., H.J. Bunge, H. Klein, U. Garbe and J.R. Schneider, High-resolution texture imaging with hard synchrotron radiation in the moving area detector technique 199 (2003) 38
Wei, S., see Kolobov, A.V. 199 (2003) 174
Weitkamp, T., see Stevenson, A.W. 199 (2003) 427
Wells, J.W., see Evans, D.A. 199 (2003) 475
Wilhelmi, O., see Moser, H.O. 199 (2003) 536
Wilkins, S.W., see Stevenson, A.W. 199 (2003) 427
Willey, T.M., see Bostedt, C. 199 (2003) 402
Wu, Z.Y., see Zhang, J. 199 (2003) 291

Xu, F.Q., see Xu, P.S. 199 (2003) 286
Xu, P.S., Y.M. Sun, C.S. Shi, F.Q. Xu and H.B. Pan, The electronic structure and spectral properties of ZnO and its defects 199 (2003) 286

Yagi, K., see Kasatani, H. 199 (2003) 49
Yagi, S., see Sardar, S.A. 199 (2003) 240
Yagi, S., K. Matsumura, Y. Nakano, E. Ikenaga, S.A. Sardar, J.A. Syed, K. Soda, E. Hashimoto, K. Tanaka and M. Taniguchi, Adsorption behavior of sulfur-containing amino acid molecule on transition metal surface studied by S K-edge NEXAFS 199 (2003) 244
Yagi, S., see Soda, K. 199 (2003) 416
Yamada, A., see Fons, P. 199 (2003) 190
Yamada, H., see Yoshida, A. 199 (2003) 370
Yamada, H., Novel X-ray source based on a tabletop synchrotron and its unique features 199 (2003) 509

Yamaguchi, S., see Higuchi, T. 199 (2003) 255
Yamamoto, T., see Muramatsu, Y. 199 (2003) 260
Yamasaki, S., see Kolobov, A.V. 199 (2003) 174
Yang, P., see Moser, H.O. 199 (2003) 536
Yokoya, A., see Fujii, K. 199 (2003) 249
Yokoya, A., see Akamatsu, K. 199 (2003) 328
Yokoya, A., K. Akamatsu and K. Fujii, Electron paramagnetic resonance induced by K-shell resonance excitation in DNA bases in solid state 199 (2003) 366
Yokoyama, K., see Matsui, J. 199 (2003) 15
Yokoyama, K., see Tsusaka, Y. 199 (2003) 19
Yoshida, A., E. Matsumoto, H. Yamada, H. Okada and A. Wakahara, Microfabrication of high quality polytetrafluoroethylene films by synchrotron radiation 199 (2003) 370
Yoshida, F., see Tsusaka, Y. 199 (2003) 19
Yoshimoto, O., see Soda, K. 199 (2003) 416
Yoshimoto, O., see Yuhara, J. 199 (2003) 422
Yoshimura, J., see Ozaki, T. 199 (2003) 81
Yoshimura, J.-i., see Suzuki, C.K. 199 (2003) 85
Youn, H.S., see Stevenson, A.W. 199 (2003) 427
Yu, K.M., see Azevedo, G. de M. 199 (2003) 179
Yu, K.M., see Ridgway, M.C. 199 (2003) 235
Yuasa, S., see Yuhara, J. 199 (2003) 422
Yuhara, J., see Soda, K. 199 (2003) 416
Yuhara, J., S. Yuasa, O. Yoshimoto, D. Nakamura, K. Soda and M. Kamada, Electronic structure of Si(1 1 1)$2\sqrt{7} \times 3$-(Pb,Sn) surface 199 (2003) 422
Yun, W., see Stevenson, A.W. 199 (2003) 427

Zahn, D.R.T., see Evans, D.A. 199 (2003) 475
Zalar, A., see Arčon, I. 199 (2003) 222
Zhang, J., Z.Y. Wu, K. Ibrahim, M.I. Abbas and X. Ju, Surface structure of α-Fe_2O_3 nanocrystal observed by O K-edge X-ray absorption spectroscopy 199 (2003) 291
Zheng, H.W., see Moser, H.O. 199 (2003) 536